

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/606,045	LYNCH ET AL.	
Examiner	Art Unit	
/BINH K. TIEU/	2614	:

SEARCHED				
Class	Subclass	Date	Examiner	
455	414.1	9/13/2007	ВКТ	
	420	1	1	
	426.1			
	426.2			
	443-444			
	448			
370	310			
ŧ,	328			
709	238			
11	249	J		
appated	(EARCH	11 28 67	BKF	
455	414.3			
	426.1			
↓	550.1			
370	556.	J	1	

INTERFERENCE SEARCHED

Date

2007

Examiner

EARCH

Subclass

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST DATABASES SEARCHES	9/12/2007			
WEST DATABASES SEARCHES	9/13/2007	вкт		
WEST DATABASES SEARCH	11/28/07	BKT.		
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Class